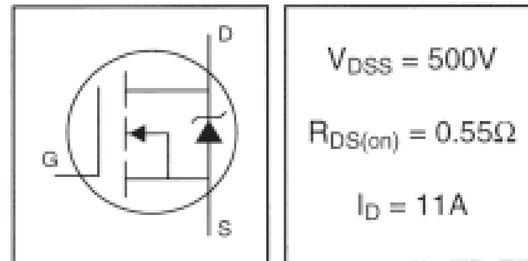
International
IOR Rectifier

PD- 95231

IRFSL11N50APbF

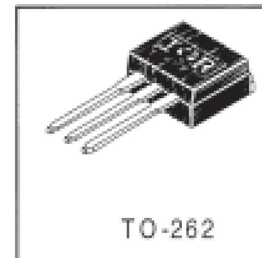
HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Paraleling
- Simple Drive Requirements
- Lead-Free



Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.



TO-262

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Absolute Maximum Ratings

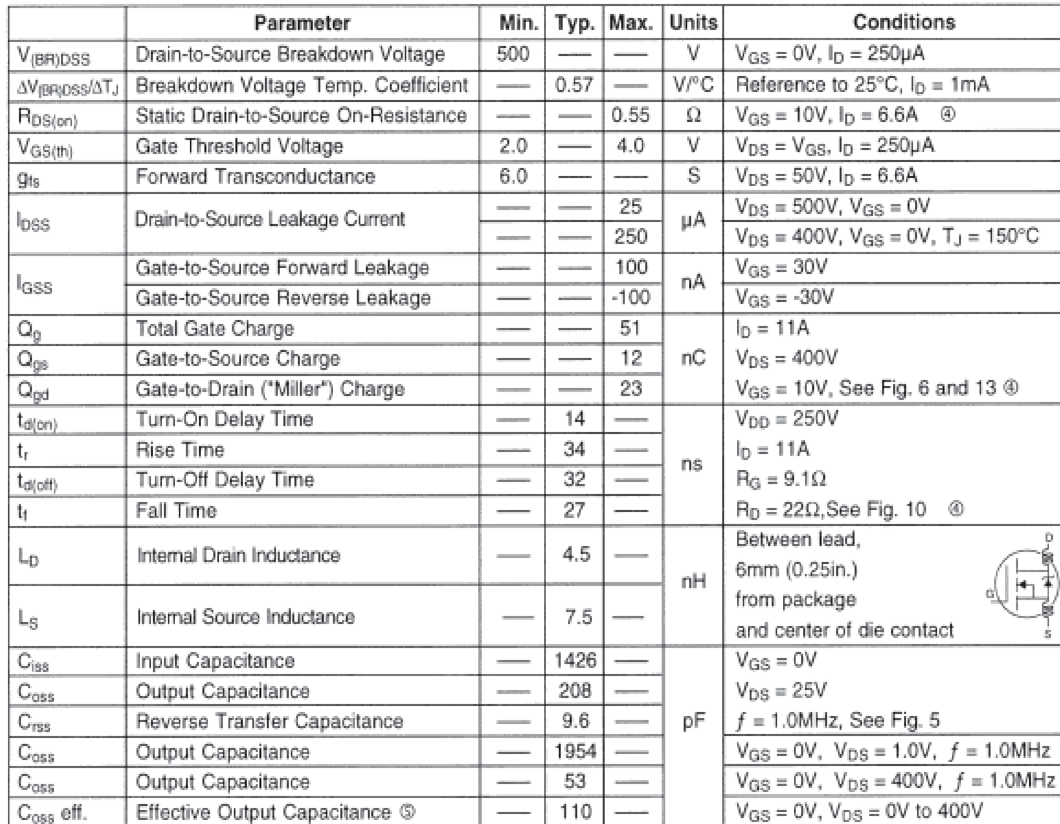
	Parameter	Max.	Units
I_D @ T_C = 25°C	Continuous Drain Current, V_{GS} @ 10V	11	A
I_D @ T_C = 100°C	Continuous Drain Current, V_{GS} @ 10V	7.0	
I_{DM}	Pulsed Drain Current ①	44	
P_D @T_C = 25°C	Power Dissipation	190	W
	Linear Derating Factor	1.3	W/°C
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy②	390	mJ
I_{AR}	Avalanche Current①	11	A
E_{AR}	Repetitive Avalanche Energy①	19	mJ
dv/dt	Peak Diode Recovery dv/dt ③	4.1	V/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 175	°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{θJC}$	Junction-to-Case	——	0.75	°C
$R_{θJA}$	Junction-to-Ambient	——	40	

04/29/04

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)



	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	500	—	—	V	V_{GS} = 0V, I_D = 250μA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.57	—	V/°C	Reference to 25°C, I_D = 1mA
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	0.55	Ω	V_{GS} = 10V, I_D = 6.6A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	4.0	V	V_{DS} = V_{GS}, I_D = 250μA
g_{fs}	Forward Transconductance	6.0	—	—	S	V_{DS} = 50V, I_D = 6.6A
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	μA	V_{DS} = 500V, V_{GS} = 0V
		—	—	250		V_{DS} = 400V, V_{GS} = 0V, T_J = 150°C
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V_{GS} = 30V
	Gate-to-Source Reverse Leakage	—	—	-100		V_{GS} = -30V
Q_g	Total Gate Charge	—	—	51	nC	I_D = 11A
Q_{gs}	Gate-to-Source Charge	—	—	12		V_{DS} = 400V
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	23		V_{GS} = 10V, See Fig. 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	—	14	—	ns	V_{DD} = 250V
t_r	Rise Time	—	34	—		I_D = 11A
$t_{d(off)}$	Turn-Off Delay Time	—	32	—		R_G = 9.1Ω
t_f	Fall Time	—	27	—		R_D = 22Ω, See Fig. 10 ④
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package
L_S	Internal Source Inductance	—	7.5	—		and center of die contact
C_{iss}	Input Capacitance	—	1426	—	pF	V_{GS} = 0V
C_{oss}	Output Capacitance	—	208	—		V_{DS} = 25V
C_{rss}	Reverse Transfer Capacitance	—	9.6	—		f = 1.0MHz, See Fig. 5
C_{oss}	Output Capacitance	—	1954	—		V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz
C_{oss}	Output Capacitance	—	53	—		V_{GS} = 0V, V_{DS} = 400V, f = 1.0MHz
C_{oss} eff.	Effective Output Capacitance ⑤	—	110	—		V_{GS} = 0V, V_{DS} = 0V to 400V

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	11	A	MOSFET symbol showing the
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	44		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage	—	—	1.5	V	T_J = 25°C, I_S = 11A, V_{GS} = 0V ④
t_{rr}	Reverse Recovery Time	—	530	790	ns	T_J = 25°C, I_F = 11A
Q_{rr}	Reverse RecoveryCharge	—	3.4	5.1	μC	di/dt = 100A/μs ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

② Starting T_J = 25°C, L = 6.4mH R_G = 25Ω, I_{AS} = 11A. (See Figure 12)

③ $I_{SD} \le$ 11A, di/dt $\le$ 185A/μs, $V_{DD} \le V_{(BR)DSS}$, $T_J \le$ 175°C

④ Pulse width $\le$ 300μs; duty cycle $\le$ 2%.

⑤ C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}

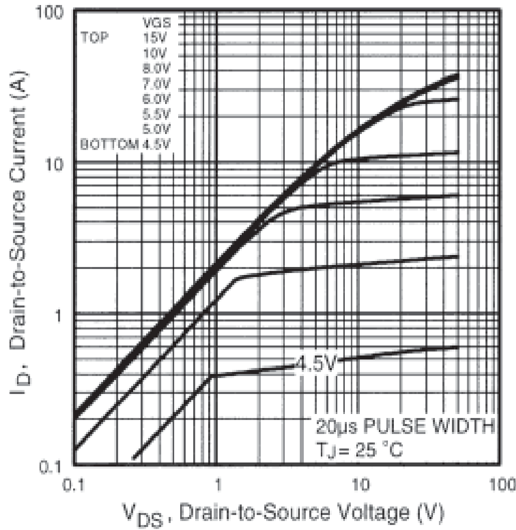


Fig 1. Typical Output Characteristics

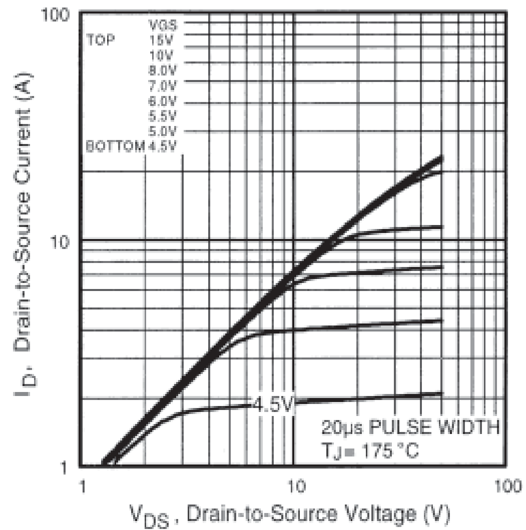


Fig 2. Typical Output Characteristics

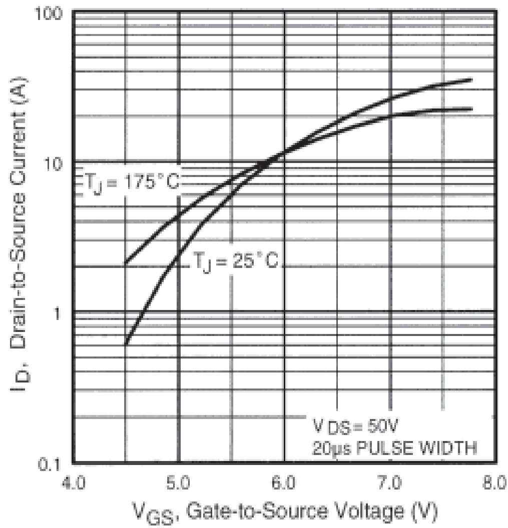


Fig 3. Typical Transfer Characteristics

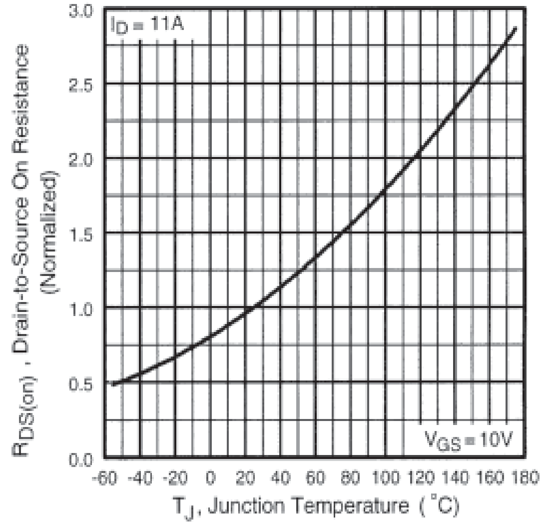


Fig 4. Normalized On-Resistance Vs. Temperature

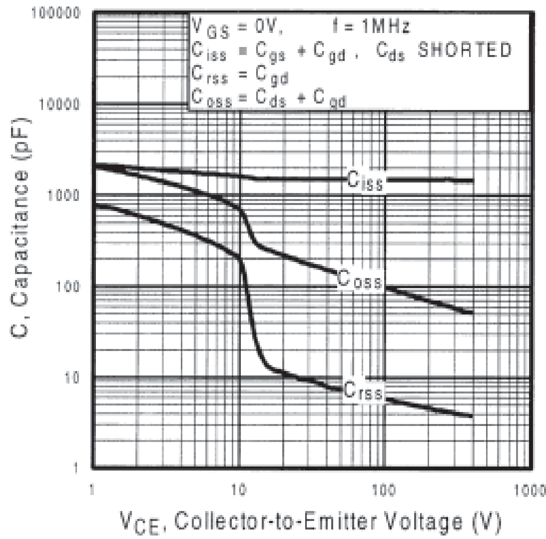


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

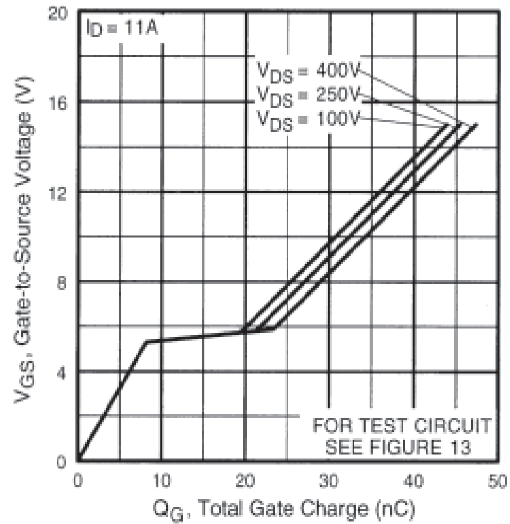


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

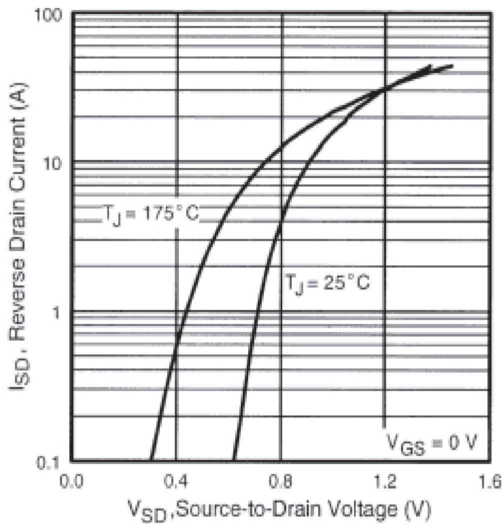


Fig 7. Typical Source-Drain Diode Forward Voltage

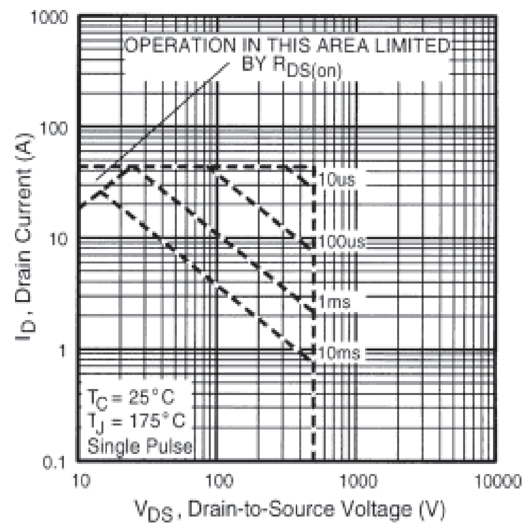


Fig 8. Maximum Safe Operating Area

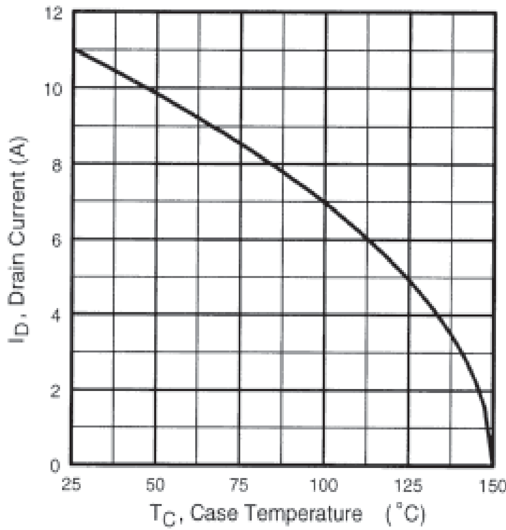


Fig 9. Maximum Drain Current Vs. Case Temperature

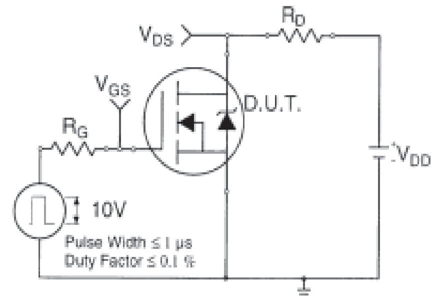


Fig 10a. Switching Time Test Circuit

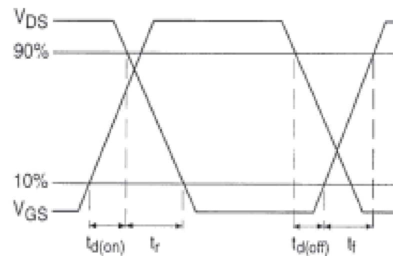


Fig 10b. Switching Time Waveforms

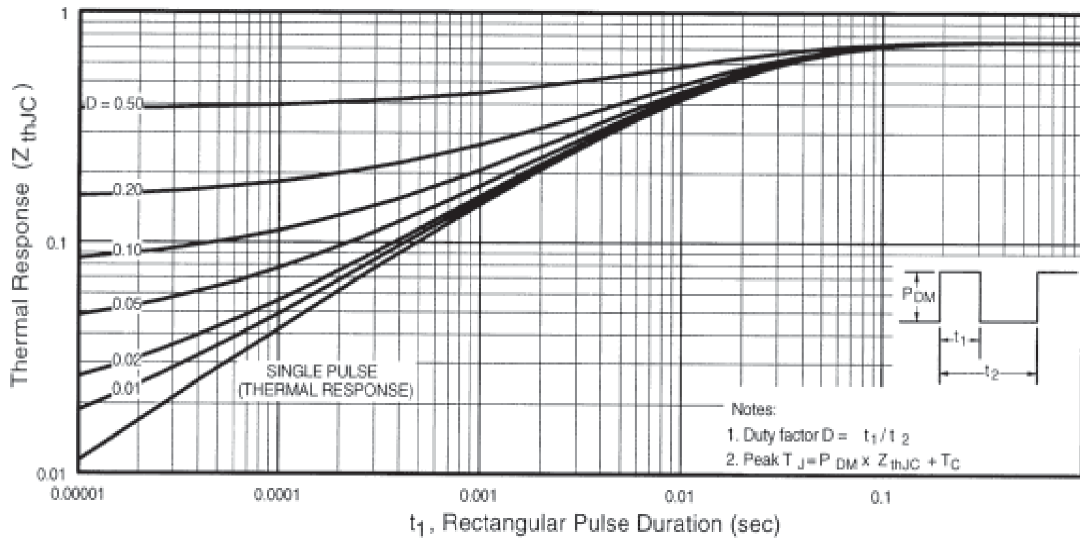


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

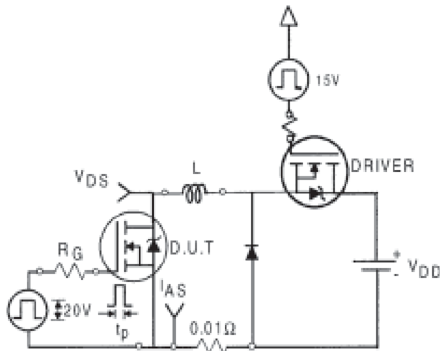


Fig 12a. Unclamped Inductive Test Circuit

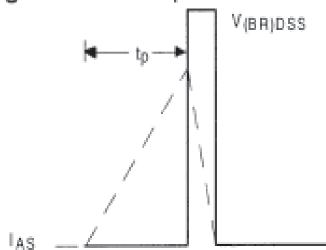


Fig 12b. Unclamped Inductive Waveforms

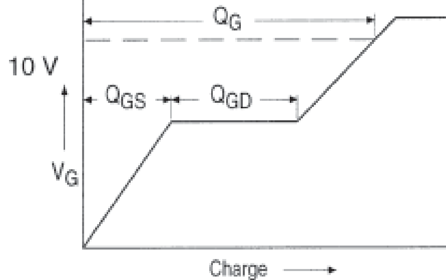


Fig 13a. Basic Gate Charge Waveform

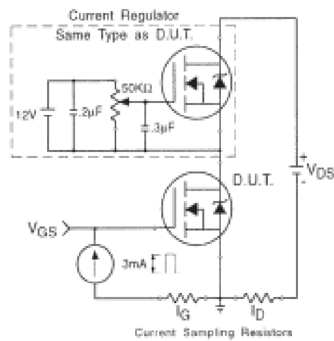


Fig 13b. Gate Charge Test Circuit

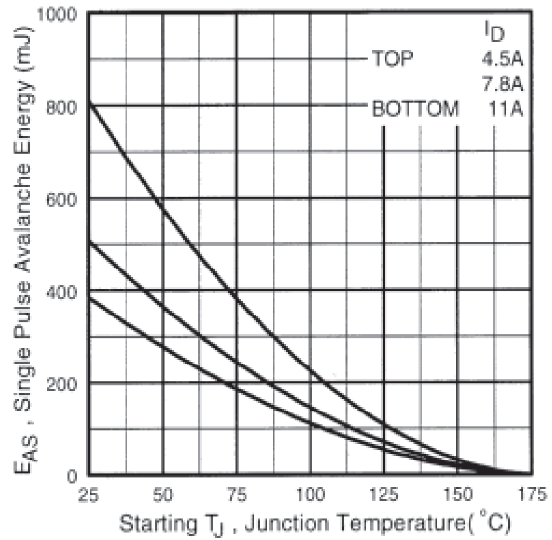


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

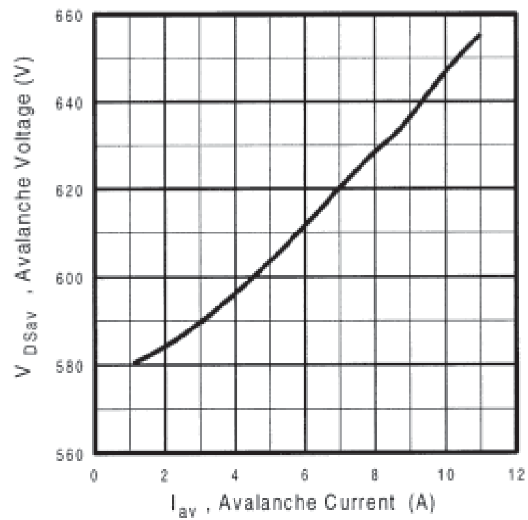
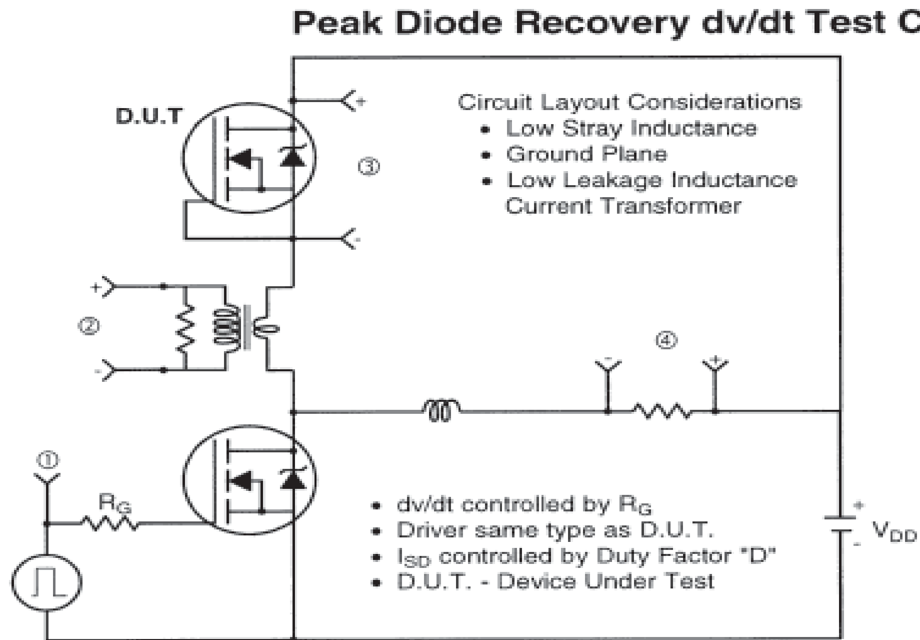
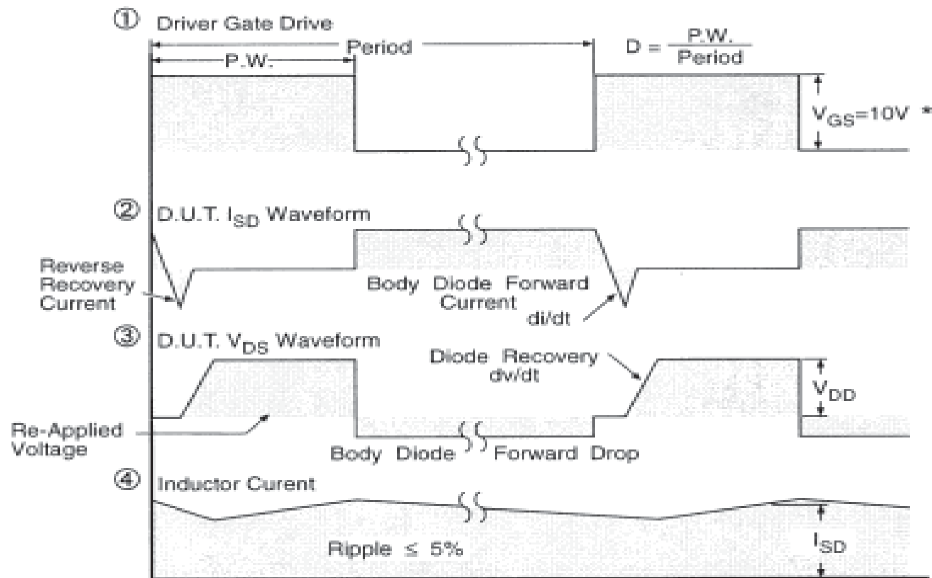


Fig 12d. Typical Drain-to-Source Voltage Vs. Avalanche Current

Peak Diode Recovery dv/dt Test Circuit



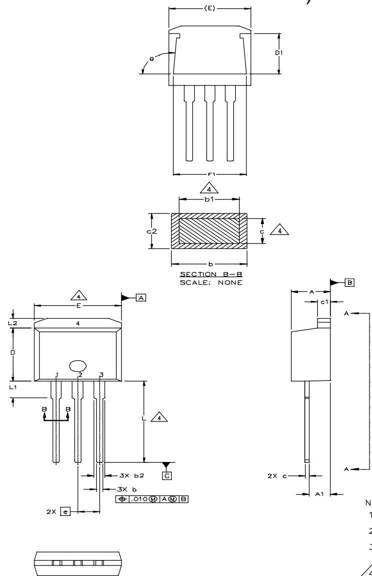


* V_{GS} = 5V for Logic Level Devices

Fig 14. For N-Channel HEXFETS

TO-262 Package Outline

Dimensions are shown in millimeters (inches)



SYMBOL	DIMENSIONS				NOTES
	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
A	4.06	4.83	.160	.190	
A1	2.03	2.92	.080	.115	
b	0.51	0.99	.020	.039	
b1	0.51	0.89	.020	.035	4
b2	1.14	1.40	.045	.055	
c	0.38	0.63	.015	.025	4
c1	1.14	1.40	.045	.055	
c2	0.43	.063	.017	.029	
D	8.51	9.65	.335	.380	3
D1	5.33		.210		
E	9.65	10.67	.380	.420	3
E1	6.22		.245		
e	2.54 BSC		.100 BSC		
L	13.46	14.09	.530	.555	
L1	3.56	3.71	.140	.146	
L2		1.65		.065	

LEAD ASSIGNMENTS

HEXFET

1.– GATE
2.– DRAIN
3.– SOURCE
4.– DRAIN

IGBT

1 – GATE
2 – COLLECTOR
3 – EMITTER

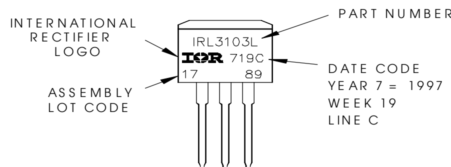
NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
4. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
5. CONTROLLING DIMENSION: INCH.

TO-262 Part Marking Information

EXAMPLE: THIS IS AN IRL3103L
LOT CODE 1789
ASSEMBLED ON WW 19, 1997
IN THE ASSEMBLY LINE "C"

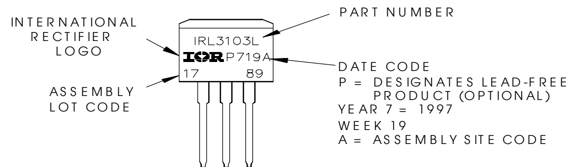
Note: "P" in assembly line position indicates "Lead-Free"



PART NUMBER

DATE CODE
YEAR 7 = 1997
WEEK 19
LINE C

OR



PART NUMBER

DATE CODE
P = DESIGNATES LEAD-FREE PRODUCT (OPTIONAL)
YEAR 7 = 1997
WEEK 19
A = ASSEMBLY SITE CODE

Data and specifications subject to change without notice.

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